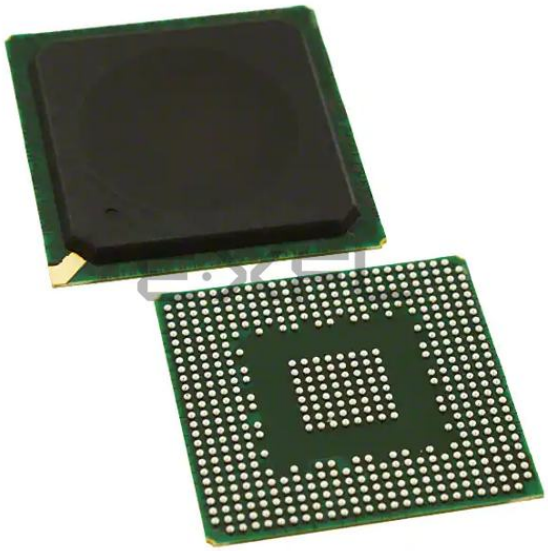

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e300c3
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	333MHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 + PHY (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	516-BBGA Exposed Pad
Supplier Device Package	516-TEPBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8313zqaffb

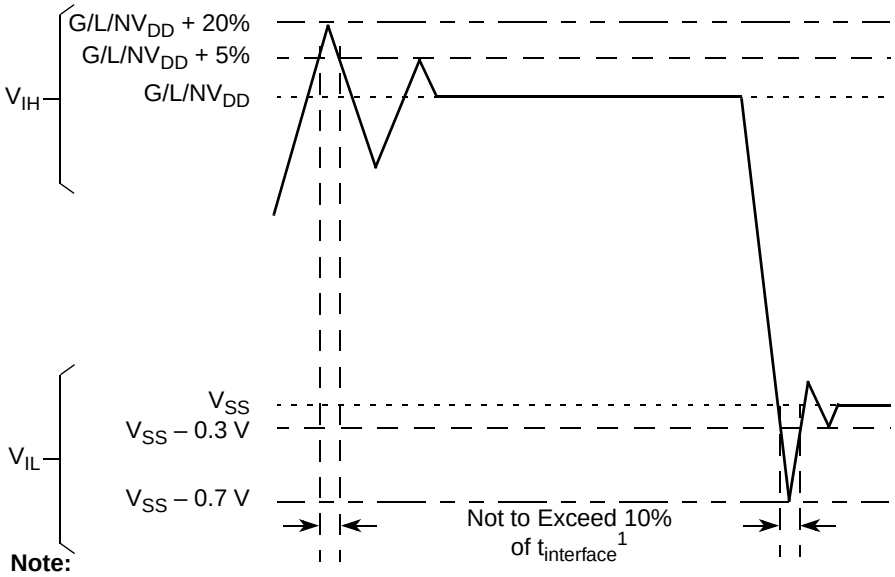
Table 2. Recommended Operating Conditions (continued)

Characteristic	Symbol	Recommended Value[1]	Unit	Current Requirement

Note:

1. GV_{DD}, NV_{DD}, AV_{DD}, and V_{DD} must track each other and must vary in the same direction—either in the positive or negative direction.
2. Some GPIO pins may operate from a 2.5-V supply when configured for other functions.
3. Min temperature is specified with T_A; Max temperature is specified with T_J.
4. All Power rails must be connected and power applied to the MPC8313 even if the IP interfaces are not used.
5. All I/O pins should be interfaced with peripherals operating at same voltage level.
6. This voltage is the input to the filter discussed in Section 22.2, "PLL Power Supply Filtering" and not necessarily the voltage at the AVDD pin, which may be reduced from VDD by the filter.

This figure shows the undershoot and overshoot voltages at the interfaces of the MPC8313E.



Note:

1. Note that $t_{interface}$ refers to the clock period associated with the bus clock interface.

Figure 2. Overshoot/Undershoot Voltage for GV_{DD}/NV_{DD}/LV_{DD}

2.1.3 Output Driver Characteristics

This table provides information on the characteristics of the output driver strengths.

Table 3. Output Drive Capability

Driver Type	Output Impedance (Ω)	Supply Voltage
Local bus interface utilities signals	42	NV_{DD} = 3.3 V
PCI signals	25	
DDR signal	18	GV_{DD} = 2.5 V

5.2 RESET AC Electrical Characteristics

This table provides the reset initialization AC timing specifications.

Table 10. RESET Initialization Timing Specifications

Parameter/Condition	Min	Max	Unit	Note
Required assertion time of $\overline{\text{HRESET}}$ or $\overline{\text{SRESET}}$ (input) to activate reset flow	32	—	$t_{PCI\_SYNC\_IN}$	1
Required assertion time of $\overline{\text{PORESET}}$ with stable clock and power applied to SYS_CLK_IN when the device is in PCI host mode	32	—	$t_{SYS\_CLK\_IN}$	2
Required assertion time of $\overline{\text{PORESET}}$ with stable clock and power applied to PCI_SYNC_IN when the device is in PCI agent mode	32	—	$t_{PCI\_SYNC\_IN}$	1
$\overline{\text{HRESET}}$ assertion (output)	512	—	$t_{PCI\_SYNC\_IN}$	1
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:3] and $\overline{\text{CFG\_CLK\_IN\_DIV}}$) with respect to negation of $\overline{\text{PORESET}}$ when the device is in PCI host mode	4	—	$t_{SYS\_CLK\_IN}$	2
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:2] and $\overline{\text{CFG\_CLKIN\_DIV}}$) with respect to negation of $\overline{\text{PORESET}}$ when the device is in PCI agent mode	4	—	$t_{PCI\_SYNC\_IN}$	1
Input hold time for POR configuration signals with respect to negation of $\overline{\text{HRESET}}$	0	—	ns	—
Time for the device to turn off POR configuration signal drivers with respect to the assertion of $\overline{\text{HRESET}}$	—	4	ns	3
Time for the device to turn on POR configuration signal drivers with respect to the negation of $\overline{\text{HRESET}}$	1	—	$t_{PCI\_SYNC\_IN}$	1, 3

Notes:
1. $t_{PCI\_SYNC\_IN}$ is the clock period of the input clock applied to PCI_SYNC_IN. When the device is In PCI host mode the primary clock is applied to the SYS_CLK_IN input, and PCI_SYNC_IN period depends on the value of $\overline{\text{CFG\_CLKIN\_DIV}}$.
2. $t_{SYS\_CLK\_IN}$ is the clock period of the input clock applied to SYS_CLK_IN. It is only valid when the device is in PCI host mode.
3. POR configuration signals consists of CFG_RESET_SOURCE[0:2] and $\overline{\text{CFG\_CLKIN\_DIV}}$.

This table provides the PLL lock times.

Table 11. PLL Lock Times

Parameter/Condition	Min	Max	Unit	Note
PLL lock times	—	100	μs	—

6 DDR and DDR2 SDRAM

This section describes the DC and AC electrical specifications for the DDR SDRAM interface. Note that DDR SDRAM is GV_{DD}(typ) = 2.5 V and DDR2 SDRAM is GV_{DD}(typ) = 1.8 V.

This figure provides the AC test load for the DDR bus.

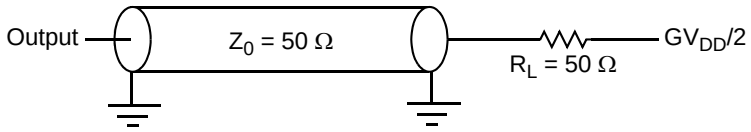


Figure 7. DDR AC Test Load

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface.

7.1 DUART DC Electrical Characteristics

This table provides the DC electrical characteristics for the DUART interface.

Table 22. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2.0	NV_{DD} + 0.3	V
Low-level input voltage NV_{DD}	V_{IL}	–0.3	0.8	V
High-level output voltage, I_{OH} = –100 μA	V_{OH}	NV_{DD} – 0.2	—	V
Low-level output voltage, I_{OL} = 100 μA	V_{OL}	—	0.2	V
Input current (0 V ≤V_{IN} ≤ NV_{DD})	I_{IN}	—	±5	μA

7.2 DUART AC Electrical Specifications

This table provides the AC timing parameters for the DUART interface.

Table 23. DUART AC Timing Specifications

Parameter	Value	Unit	Note
Minimum baud rate	256	baud	—
Maximum baud rate	> 1,000,000	baud	1
Oversample rate	16	—	2

Notes:
1. Actual attainable baud rate is limited by the latency of interrupt processing.
2. The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

8 Ethernet: Three-Speed Ethernet, MII Management

This section provides the AC and DC electrical characteristics for three-speed, 10/100/1000, and MII management.

8.1 Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—MII/RMII/RGMII/SGMII/RTBI Electrical Characteristics

The electrical characteristics specified here apply to all the media independent interface (MII), reduced gigabit media independent interface (RGMII), serial gigabit media independent interface (SGMII), and reduced ten-bit interface (RTBI) signals except management data input/output (MDIO) and management data clock (MDC). The RGMII and RTBI interfaces are defined for 2.5 V, while the MII interface can be operated at 3.3 V. The RMII and SGMII interfaces can be operated at either 3.3 or 2.5 V. The RGMII and RTBI interfaces follow the Hewlett-Packard reduced pin-count interface for *Gigabit Ethernet Physical Layer Device Specification Version 1.2*a (9/22/2000). The electrical characteristics for MDIO and MDC are specified in Section 8.5, "Ethernet Management Interface Electrical Characteristics."

8.1.1 TSEC DC Electrical Characteristics

All RGMII, RMII, and RTBI drivers and receivers comply with the DC parametric attributes specified in Table 24 and Table 25. The RGMII and RTBI signals are based on a 2.5-V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

NOTE

eTSEC should be interfaced with peripheral operating at same voltage level.

Table 24. MII DC Electrical Characteristics

Parameter	Symbol	Conditions		Min	Max	Unit
Supply voltage 3.3 V	LV_{DDA}/LV_{DDB}	—		2.97	3.63	V
Output high voltage	V_{OH}	I_{OH} = –4.0 mA	LV_{DDA} or LV_{DDB} = Min	2.40	LV_{DDA} + 0.3 or LV_{DDB} + 0.3	V
Output low voltage	V_{OL}	I_{OL} = 4.0 mA	LV_{DDA} or LV_{DDB} = Min	V_{SS}	0.50	V
Input high voltage	V_{IH}	—	—	2.0	LV_{DDA} + 0.3 or LV_{DDB} + 0.3	V
Input low voltage	V_{IL}	—	—	–0.3	0.90	V
Input high current	I_{IH}	V_{IN}[1] = LV_{DDA} or LV_{DDB}		—	40	μA
Input low current	I_{IL}	V_{IN}[1] = VSS		–600	—	μA

Note:
1. The symbol V_{IN}, in this case, represents the LV_{IN} symbol referenced in Table 1 and Table 2.

Table 25. RGMII/RTBI DC Electrical Characteristics

Parameters	Symbol	Conditions	Min	Max	Unit
Supply voltage 2.5 V	LV_{DDA}/LV_{DDB}	—	2.37	2.63	V

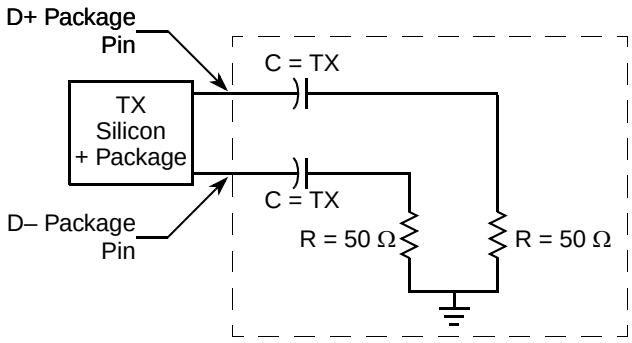
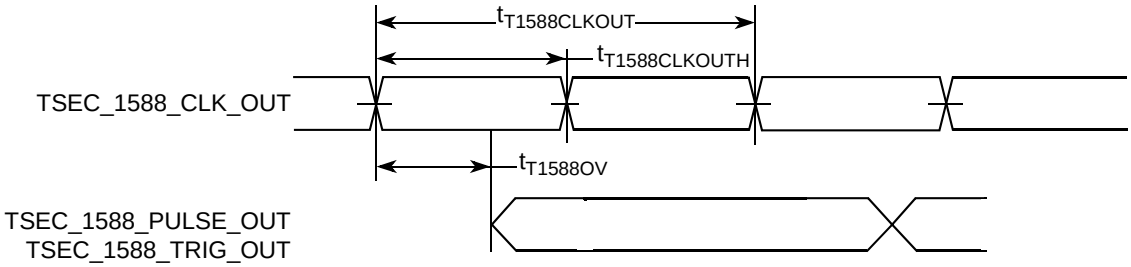


Figure 18. SGMII AC Test/Measurement Load

8.4 eTSEC IEEE 1588 AC Specifications

This figure provides the data and command output timing diagram.



Note: The output delay is count starting rising edge if $t_{T1588CLKOUT}$ is non-inverting. Otherwise, it is count starting falling edge.

Figure 19. eTSEC IEEE 1588 Output AC Timing

This figure provides the data and command input timing diagram.

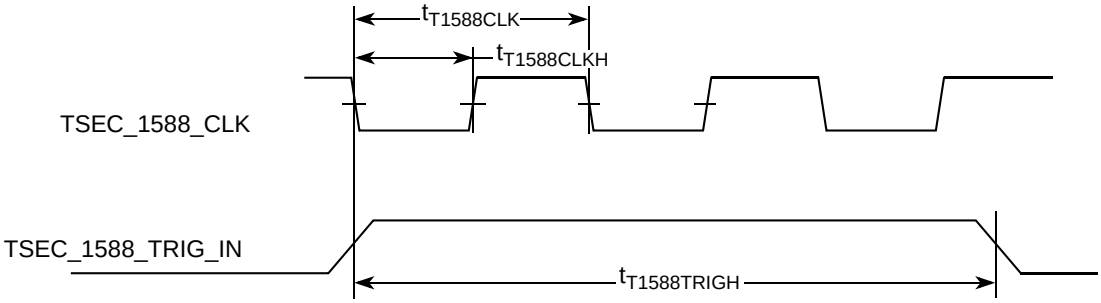


Figure 20. eTSEC IEEE 1588 Input AC Timing

This table lists the IEEE 1588 AC timing specifications.

Table 36. eTSEC IEEE 1588 AC Timing Specifications

At recommended operating conditions with L/TV_{DD} of 3.3 V ± 5%.

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
TSEC_1588_CLK clock period	$t_{T1588CLK}$	3.8	—	$T_{RX\_CLK} \times 9$	ns	1, 3
TSEC_1588_CLK duty cycle	$t_{T1588CLKH}/t_{T1588CLK}$	40	50	60	%	

of the differential pair must have a single-ended swing less than 800 mV and greater than 200 mV. This requirement is the same for both external DC-coupled or AC-coupled connection.

— For external DC-coupled connection, as described in Section 9.2.1, "SerDes Reference Clock Receiver Characteristics," the maximum average current requirements sets the requirement for average voltage (common mode voltage) to be between 100 and 400 mV. Figure 24 shows the SerDes reference clock input requirement for the DC-coupled connection scheme.

— For external AC-coupled connection, there is no common mode voltage requirement for the clock driver. Since the external AC-coupling capacitor blocks the DC level, the clock driver and the SerDes reference clock receiver operate in different command mode voltages. The SerDes reference clock receiver in this connection scheme has its common mode voltage set to $XCOREV_{SS}$. Each signal wire of the differential inputs is allowed to swing below and above the command mode voltage ($XCOREV_{SS}$). Figure 25 shows the SerDes reference clock input requirement for AC-coupled connection scheme.

- Single-ended mode

— The reference clock can also be single-ended. The SD_REF_CLK input amplitude (single-ended swing) must be between 400 and 800 mV peak-to-peak (from V_{min} to V_{max}) with $\overline{\text{SD\_REF\_CLK}}$ either left unconnected or tied to ground.

— The SD_REF_CLK input average voltage must be between 200 and 400 mV. Figure 26 shows the SerDes reference clock input requirement for the single-ended signaling mode.

— To meet the input amplitude requirement, the reference clock inputs might need to be DC or AC coupled externally. For the best noise performance, the reference of the clock could be DC or AC coupled into the unused phase ($\overline{\text{SD\_REF\_CLK}}$) through the same source impedance as the clock input (SD_REF_CLK) in use.

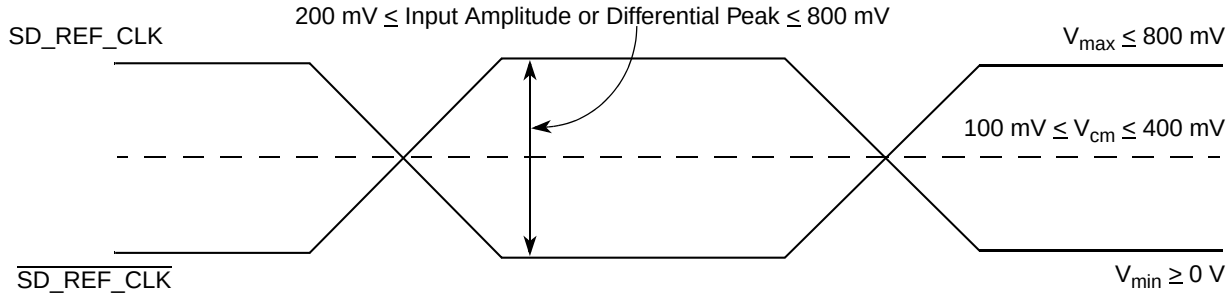


Figure 24. Differential Reference Clock Input DC Requirements (External DC-Coupled)

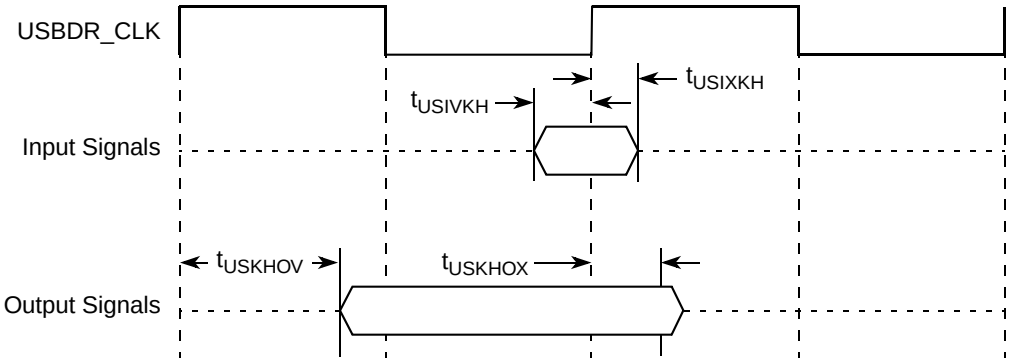


Figure 35. USB Signals

10.2 On-Chip USB PHY

This section describes the DC and AC electrical specifications for the on-chip USB PHY of the MPC8313E. See Chapter 7 in the *USB Specifications Rev. 2*, for more information.

This table provides the USB clock input (USB_CLK_IN) DC timing specifications.

Table 42. USB_CLK_IN DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
Input high voltage	V_{IH}	2.7	NV_{DD} + 0.3	V
Input low voltage	V_{IL}	–0.3	0.4	V

This table provides the USB clock input (USB_CLK_IN) AC timing specifications.

Table 43. USB_CLK_IN AC Timing Specifications

Parameter/Condition	Conditions	Symbol	Min	Typ	Max	Unit
Frequency range	—	$f_{USB\_CLK\_IN}$	—	24	48	MHz
Clock frequency tolerance	—	t_{CLK_TOL}	–0.005	0	0.005	%
Reference clock duty cycle	Measured at 1.6 V	t_{CLK_DUTY}	40	50	60	%
Total input jitter/time interval error	Peak-to-peak value measured with a second order high-pass filter of 500 kHz bandwidth	t_{CLK_PJ}	—	—	200	ps

Table 45. Local Bus General Timing Parameters (continued)

Parameter	Symbol[1]	Min	Max	Unit	Note

Notes:
1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1).
2. All timings are in reference to falling edge of LCLK0 (for all outputs and for $\overline{\text{LGTA}}$ and LUPWAIT inputs) or rising edge of LCLK0 (for all other inputs).
3. All signals are measured from $NV_{DD}/2$ of the rising/falling edge of LCLK0 to $0.4 \times NV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. $t_{LBOTOT1}$ and $t_{LALETOT1}$ should be used when RCWH[LALE] is not set and the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
6. $t_{LBOTOT2}$ and $t_{LALETOT2}$ should be used when RCWH[LALE] is set and the load on LALE output pin is at least 10 pF less than the load on LAD output pins.
7. $t_{LBOTOT3}$ and $t_{LALETOT3}$ should be used when RCWH[LALE] is set and the load on LALE output pin equals to the load on LAD output pins.
8. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

This figure provides the AC test load for the local bus.

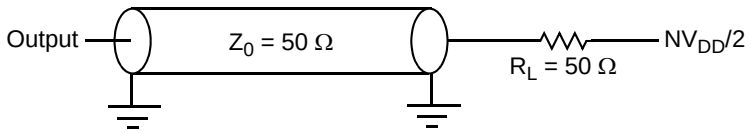


Figure 36. Local Bus AC Test Load

15.2 Timers AC Timing Specifications

This table provides the Timers input and output AC timing specifications.

Table 54. Timers Input AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Unit
Timers inputs—minimum pulse width	t_{TIWID}	20	ns

Notes:
1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of SYS_CLK_IN. Timings are measured at the pin.
2. Timers inputs and outputs are asynchronous to any visible clock. Timers outputs should be synchronized before use by any external synchronous logic. Timers inputs are required to be valid for at least t_{TIWID} ns to ensure proper operation

This figure provides the AC test load for the Timers.

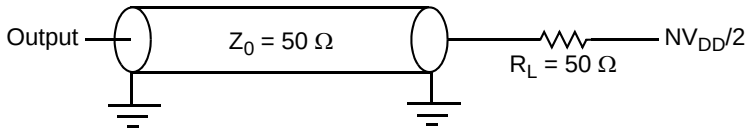


Figure 51. Timers AC Test Load

16 GPIO

This section describes the DC and AC electrical specifications for the GPIO.

16.1 GPIO DC Electrical Characteristics

This table provides the DC electrical characteristics for the GPIO when the GPIO pins are operating from a 3.3-V supply.

Table 55. GPIO (When Operating at 3.3 V) DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –8.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 8.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	NV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le NV_{DD}$	—	±5	μA

Note:
1. This specification only applies to GPIO pins that are operating from a 3.3-V supply. See Table 62 for the power supply listed for the individual GPIO signal.

19.3 Pinout Listings

This table provides the pin-out listing for the MPC8313E, TEPBGAII package.

Table 62. MPC8313E TEPBGAII Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Note
DDR Memory Controller Interface				
MEMC_MDQ0	A8	I/O	GV_{DD}	—
MEMC_MDQ1	A9	I/O	GV_{DD}	—
MEMC_MDQ2	C10	I/O	GV_{DD}	—
MEMC_MDQ3	C9	I/O	GV_{DD}	—
MEMC_MDQ4	E9	I/O	GV_{DD}	—
MEMC_MDQ5	E11	I/O	GV_{DD}	—
MEMC_MDQ6	E10	I/O	GV_{DD}	—
MEMC_MDQ7	C8	I/O	GV_{DD}	—
MEMC_MDQ8	E8	I/O	GV_{DD}	—
MEMC_MDQ9	A6	I/O	GV_{DD}	—
MEMC_MDQ10	B6	I/O	GV_{DD}	—
MEMC_MDQ11	C6	I/O	GV_{DD}	—
MEMC_MDQ12	C7	I/O	GV_{DD}	—
MEMC_MDQ13	D7	I/O	GV_{DD}	—
MEMC_MDQ14	D6	I/O	GV_{DD}	—
MEMC_MDQ15	A5	I/O	GV_{DD}	—
MEMC_MDQ16	A19	I/O	GV_{DD}	—
MEMC_MDQ17	D18	I/O	GV_{DD}	—
MEMC_MDQ18	A17	I/O	GV_{DD}	—
MEMC_MDQ19	E17	I/O	GV_{DD}	—
MEMC_MDQ20	E16	I/O	GV_{DD}	—
MEMC_MDQ21	C18	I/O	GV_{DD}	—
MEMC_MDQ22	D19	I/O	GV_{DD}	—
MEMC_MDQ23	C19	I/O	GV_{DD}	—
MEMC_MDQ24	E19	I/O	GV_{DD}	—
MEMC_MDQ25	A22	I/O	GV_{DD}	—
MEMC_MDQ26	C21	I/O	GV_{DD}	—
MEMC_MDQ27	C20	I/O	GV_{DD}	—
MEMC_MDQ28	A21	I/O	GV_{DD}	—

Table 62. MPC8313E TEPBGAII Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Note
MEMC_MDQ29	A20	I/O	GV_{DD}	—
MEMC_MDQ30	C22	I/O	GV_{DD}	—
MEMC_MDQ31	B22	I/O	GV_{DD}	—
MEMC_MDM0	B7	O	GV_{DD}	—
MEMC_MDM1	E6	O	GV_{DD}	—
MEMC_MDM2	E18	O	GV_{DD}	—
MEMC_MDM3	E20	O	GV_{DD}	—
MEMC_MDQS0	A7	I/O	GV_{DD}	—
MEMC_MDQS1	E7	I/O	GV_{DD}	—
MEMC_MDQS2	B19	I/O	GV_{DD}	—
MEMC_MDQS3	A23	I/O	GV_{DD}	—
MEMC_MBA0	D15	O	GV_{DD}	—
MEMC_MBA1	A18	O	GV_{DD}	—
MEMC_MBA2	A15	O	GV_{DD}	—
MEMC_MA0	E12	O	GV_{DD}	—
MEMC_MA1	D11	O	GV_{DD}	—
MEMC_MA2	B11	O	GV_{DD}	—
MEMC_MA3	A11	O	GV_{DD}	—
MEMC_MA4	A12	O	GV_{DD}	—
MEMC_MA5	E13	O	GV_{DD}	—
MEMC_MA6	C12	O	GV_{DD}	—
MEMC_MA7	E14	O	GV_{DD}	—
MEMC_MA8	B15	O	GV_{DD}	—
MEMC_MA9	C17	O	GV_{DD}	—
MEMC_MA10	C13	O	GV_{DD}	—
MEMC_MA11	A16	O	GV_{DD}	—
MEMC_MA12	C15	O	GV_{DD}	—
MEMC_MA13	C16	O	GV_{DD}	—
MEMC_MA14	E15	O	GV_{DD}	—
$\overline{\text{MEMC\_MWE}}$	B18	O	GV_{DD}	—
$\overline{\text{MEMC\_MRAS}}$	C11	O	GV_{DD}	—
$\overline{\text{MEMC\_MCAS}}$	B10	O	GV_{DD}	—

Table 62. MPC8313E TEPBGAII Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Note
TSEC1_TXD1/TSEC_1588_PP2	AD6	O	LV_{DDB}	—
TSEC1_TXD0/USBDR_STP/TSEC_1588_PP3	AD5	O	LV_{DDB}	—
TSEC1_TX_EN/TSEC_1588_ALARM1	AB7	O	LV_{DDB}	—
TSEC1_TX_ER/TSEC_1588_ALARM2	AB8	O	LV_{DDB}	—
TSEC1_GTX_CLK125	AE1	I	LV_{DDB}	—
TSEC1_MDC/LB_POR_CFG_BOOT_ECC_DIS	AF6	O	NV_{DD}	9, 11
TSEC1_MDIO	AB9	I/O	NV_{DD}	—
ETSEC2				
TSEC2_COL/GTM1_TIN4/GTM2_TIN3/GPIO15	AB4	I/O	LV_{DDA}	—
TSEC2_CRS/$\overline{\text{GTM1\_TGATE4}}$/$\overline{\text{GTM2\_TGATE3}}$/GPIO16	AB3	I/O	LV_{DDA}	—
TSEC2_GTX_CLK/$\overline{\text{GTM1\_TOUT4}}$/$\overline{\text{GTM2\_TOUT3}}$/GPIO17	AC1	I/O	LV_{DDA}	12
TSEC2_RX_CLK/GTM1_TIN2/GTM2_TIN1/GPIO18	AC2	I/O	LV_{DDA}	—
TSCE2_RX_DV/$\overline{\text{GTM1\_TGATE2}}$/$\overline{\text{GTM2\_TGATE1}}$/GPIO19	AA3	I/O	LV_{DDA}	—
TSEC2_RXD3/GPIO20	Y5	I/O	LV_{DDA}	—
TSEC2_RXD2/GPIO21	AA4	I/O	LV_{DDA}	—
TSEC2_RXD1/GPIO22	AB2	I/O	LV_{DDA}	—
TSEC2_RXD0/GPIO23	AA5	I/O	LV_{DDA}	—
TSEC2_RX_ER/$\overline{\text{GTM1\_TOUT2}}$/$\overline{\text{GTM2\_TOUT1}}$/GPIO24	AA2	I/O	LV_{DDA}	—
TSEC2_TX_CLK/GPIO25	AB1	I/O	LV_{DDA}	—
TSEC2_TXD3/CFG_RESET_SOURCE0	W3	I/O	LV_{DDA}	—
TSEC2_TXD2/CFG_RESET_SOURCE1	Y1	I/O	LV_{DDA}	—
TSEC2_TXD1/CFG_RESET_SOURCE2	W5	I/O	LV_{DDA}	—
TSEC2_TXD0/CFG_RESET_SOURCE3	Y3	I/O	LV_{DDA}	—
TSEC2_TX_EN/GPIO26	AA1	I/O	LV_{DDA}	—
TSEC2_TX_ER/GPIO27	W1	I/O	LV_{DDA}	—
SGMII PHY				
TXA	U3	O		—
$\overline{\text{TXA}}$	V3	O		—
RXA	U1	I		—
$\overline{\text{RXA}}$	V1	I		—
TXB	P4	O		—
$\overline{\text{TXB}}$	N4	O		—

20.2 Core PLL Configuration

RCWL[COREPLL] selects the ratio between the internal coherent system bus clock (*csb_clk*) and the e300 core clock (*core_clk*). This table shows the encodings for RCWL[COREPLL]. COREPLL values that are not listed in this table should be considered as reserved.

NOTE

Core VCO frequency = core frequency × VCO divider. The VCO divider, which is determined by RCWLR[COREPLL], must be set properly so that the core VCO frequency is in the range of 400–800 MHz.

Table 67. e300 Core PLL Configuration

RCWL[COREPLL]			***core_clk* : *csb_clk* Ratio**[1]	**VCO Divider (VCOD)**[3]
0–1	**2–5**	**6**		
nn	**0000**	0	PLL bypassed (PLL off, *csb_clk* clocks core directly)	PLL bypassed (PLL off, *csb_clk* clocks core directly)
11	***nnnn***	n	n/a	n/a
00	**0001**	0	1:1	2
01	**0001**	0	1:1	4
10	**0001**	0	1:1	8
00	**0001**	1	1.5:1	2
01	**0001**	1	1.5:1	4
10	**0001**	1	1.5:1	8
00	**0010**	0	2:1	2
01	**0010**	0	2:1	4
10	**0010**	0	2:1	8
00	**0010**	1	2.5:1	2
01	**0010**	1	2.5:1	4
10	**0010**	1	2.5:1	8
00	**0011**	0	3:1	2
01	**0011**	0	3:1	4
10	**0011**	0	3:1	8

Note:

1. For *core_clk:csb_clk* ratios of 2.5:1 and 3:1, the *core_clk* must not exceed its maximum operating frequency of 333 MHz.
2. Core VCO frequency = core frequency × VCO divider. Note that VCO divider has to be set properly so that the core VCO frequency is in the range of 400–800 MHz.

Table 69. Package Thermal Characteristics for TEPBGAII (continued)

Characteristic	Board Type	Symbol	TEPBGA II	Unit	Note
Junction-to-case	—	$R_{\theta JC}$	8	°C/W	5
Junction-to-package top	Natural convection	Ψ_{JT}	7	°C/W	6

Note:

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single layer board horizontal. Board meets JESD51-9 specification.
3. Per JEDEC JESD51-6 with the board horizontal.
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).
6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JT.

21.2 Thermal Management Information

For the following sections, $P_D = (V_{DD} \times I_{DD}) + P_{I/O}$, where $P_{I/O}$ is the power dissipation of the I/O drivers.

21.2.1 Estimation of Junction Temperature with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_J = junction temperature (°C)
T_A = ambient temperature for the package (°C)
$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)
P_D = power dissipation in the package (W)

The junction-to-ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. As a general statement, the value obtained on a single layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

21.2.2 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For many natural convection and especially closed box applications, the board temperature at the perimeter

(edge) of the package is approximately the same as the local air temperature near the device. Specifying the local ambient conditions explicitly as the board temperature provides a more precise description of the local ambient conditions that determine the temperature of the device.

At a known board temperature, the junction temperature is estimated using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

T_J = junction temperature (°C)
T_B = board temperature at the package perimeter (°C)
$R_{\theta JB}$ = junction-to-board thermal resistance (°C/W) per JESD51–8
P_D = power dissipation in the package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

21.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature (°C)
T_T = thermocouple temperature on top of package (°C)
Ψ_{JT} = thermal characterization parameter (°C/W)
P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

21.2.4 Heat Sinks and Junction-to-Case Thermal Resistance

In some application environments, a heat sink is required to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)
$R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)
$R_{\theta CA}$ = case-to- ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the airflow around the device, the interface material, the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

To illustrate the thermal performance of the devices with heat sinks, the thermal performance has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, airflow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

Table 70. Thermal Resistance for TEPBGAII with Heat Sink in Open Flow

Heat Sink Assuming Thermal Grease	Airflow	Thermal Resistance (°C/W)
Wakefield 53 × 53 × 2.5 mm pin fin	Natural convection	13.0
	0.5 m/s	10.6
	1 m/s	9.7
	2 m/s	9.2
	4 m/s	8.9
Aavid 35 × 31 × 23 mm pin fin	Natural convection	14.4
	0.5 m/s	11.3
	1 m/s	10.5
	2 m/s	9.9
	4 m/s	9.4
Aavid 30 × 30 × 9.4 mm pin fin	Natural convection	16.5
	0.5 m/s	13.5
	1 m/s	12.1
	2 m/s	10.9
	4 m/s	10.0
Aavid 43 × 41 × 16.5 mm pin fin	Natural convection	14.5
	0.5 m/s	11.7
	1 m/s	10.5
	2 m/s	9.7
	4 m/s	9.2

Accurate thermal design requires thermal modeling of the application environment using computational fluid dynamics software which can model both the conduction cooling and the convection cooling of the air moving through the application. Simplified thermal models of the packages can be assembled using the junction-to-case and junction-to-board thermal resistances listed in Table 70. More detailed thermal models can be made available on request.

This table summarizes the signal impedance targets. The driver impedance are targeted at minimum V_{DD}, nominal NV_{DD}, 105°C.

Table 71. Impedance Characteristics

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	PCI Signals (Not Including PCI Output Clocks)	PCI Output Clocks (Including PCI_SYNC_OUT)	DDR DRAM	Symbol	Unit
R_N	42 Target	25 Target	42 Target	20 Target	Z_0	Ω
R_P	42 Target	25 Target	42 Target	20 Target	Z_0	Ω
Differential	NA	NA	NA	NA	Z_{DIFF}	Ω

Note: Nominal supply voltages. See Table 1, T_J = 105 °C.

22.7 Configuration Pin Muxing

The MPC8313E provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 kΩ on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While $\overline{\text{HRESET}}$ is asserted however, these pins are treated as inputs. The value presented on these pins while $\overline{\text{HRESET}}$ is asserted, is latched when $\overline{\text{PORESET}}$ deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Careful board layout with stubless connections to these pull-up/pull-down resistors coupled with the large value of the pull-up/pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

22.8 Pull-Up Resistor Requirements

The MPC8313E requires high resistance pull-up resistors (10 kΩ is recommended) on open drain type pins including I^2C, and IPIC (integrated programmable interrupt controller).

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 61. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions because most have asynchronous behavior and spurious assertion, which give unpredictable results.

Refer to the *PCI 2.2 Specification*, for all pull-ups required for PCI.

22.9 JTAG Configuration Signals

Boundary scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in IEEE 1149.1, but is provided on any Freescale devices that are built on Power Architecture technology. The device requires $\overline{\text{TRST}}$ to be asserted during reset conditions to ensure the JTAG boundary logic does not interfere with normal chip operation. While it is possible to force the TAP controller to the reset state using only the TCK and TMS signals, systems generally assert $\overline{\text{TRST}}$ during power-on reset. Because the JTAG interface is also used for accessing the common on-chip processor (COP) function, simply tying $\overline{\text{TRST}}$ to $\overline{\text{PORESET}}$ is not practical.

24 Revision History

This table summarizes a revision history for this document.

Table 73. Document Revision History

Rev. Number	Date	Substantive Change(s)
4	11/2011	• In Table 2, added following notes: – Note 3: Min temperature is specified with T_A; Max temperature is specified with T_J – Note 4: All Power rails must be connected and power applied to the MPC8313 even if the IP interfaces are not used. – Note 5: All I/O pins should be interfaced with peripherals operating at same voltage level. – Note 6: This voltage is the input to the filter discussed in Section 22.2, “PLL Power Supply Filtering.” and not necessarily the voltage at the AVDD pin, which may be reduced from VDD by the filter • Decoupled PCI_CLK and SYS_CLK_IN rise and fall times in Table 8. Relaxed maximum rise/fall time of SYS_CLK_IN to 4ns. • Added a note in Table 27 stating “The frequency of RX_CLK should not exceed the TX_CLK by more than 300 ppm." • In Table 30: – Changed max value of t_{skrgt} in “Data to clock input skew (at receiver)” row from 2.8 to 2.6. – Added Note 7, stating that, “The frequency of RX_CLK should not exceed the GTX_CLK125 by more than 300 ppm.” • Added a note stating “eTSEC should be interfaced with peripheral operating at same voltage level” in Section 8.1.1, “TSEC DC Electrical Characteristics.” • TSEC1_MDC and TSEC_MDIO are powered at 3.3V by NVDD. Replaced LVDDA/LVDDB with NVDD and removed instances of 2.5V at several places in Section 8.5, “Ethernet Management Interface Electrical Characteristics.” • In Table 43, changed min/max values of t_{CLK_TOL} from 0.05 to 0.005. • In Table 62: – Added Note 2 for LGPL4 in showing LGPL4 as open-drain. – Removed Note 2 from TSEC1_MDIO. – Added Note 10: This pin has an internal pull-up. – Added Note 11: This pin has an internal pull-down. – Added Note 12: “In MII mode, GTX_CLK should be pulled down by 300 Ω to V_{SS}” to TSEC1_GTX_CLK and TSEC2_GTX_CLK. • In Section 19.1, “Package Parameters for the MPC8313E TEPBGAII,” replaced "5.5 Sn/0.5 Cu/4 Ag" with "Sn/3.5 Ag." • Added foot note 3 in Table 65 stating “The VCO divider needs to be set properly so that the System PLL VCO frequency is in the range of 450–750 MHz.” • In Table 72: – Added AD = 266 and D = 266. – Added “C = 2.2” in “Revision level” column. – Added Note 4. • Changed resitor from 1.0 Ω to 10 Ω in Figure 58. • Replaced LCCR with LCRR throughout. • Added high-speed to USB Phy description.
3	01/2009	• Table 72, in column aa, changed to AG = 400 MHz.
2.2	12/2008	• Made cross-references active for sections, figures, and tables.
2.1	12/2008	• Added Figure 2, after Table 2 and renumbered the following figures.

Table 73. Document Revision History (continued)

Rev. Number	Date	Substantive Change(s)
1	3/2008	• Replaced OVDD with NV_{DD} everywhere • Added XCOREVDD and XPADVDD to Table 1 • Moved VDD and VDDC to the top of the table before SerDes supplies in Table 2 • In Table 2 split DDR row into two from total current requirement of 425 mA. One for DDR1 (131 mA) and other for DDR2 (140 mA). • In Table 2 corrected current requirement numbers for NV_{DD} from 27 mA to 74 mA, LV_{DD} from 60 mA to 16 mA, LV_{DDA} from 85 mA to 22 mA and LV_{DDB} from 85 mA to 44 mA. • In Table 2 corrected Vdd and Vddc current requirements from 560 mA and 454 mA to 469 and 377 mA, respectively. Corrected Avdd1 and Avdd2 current requirements from 10 mA to 2–3 mA, and XCOREVDD from 100 mA to 170 mA. • In Table 2, added row stating junction temperature range of 0 to 105°C. Added footnote 2 stating GPIO pins may operate from 2.5-V supply as well when configured for different functionality. • In Section 2.1.2, “Power Supply Voltage Specification,” added a note describing the purpose of Table 2. • In Section 3, “Power Characteristics,” added a note describing the purpose of Table 5. • Rewrote Section 2.2, “Power Sequencing,” and added Figure 3. • In Table 4, added “but do include core, USB PLL, and a portion of SerDes digital power...” to Note 1. • In Table 4 corrected “Typical power” to “Maximum power” in note 2 and added a note for Typical Power. • In Table 4 removed 266-MHz row as 266-MHz core parts are not offered. • In Table 5, moved Local bus typical power dissipation under LVdd. • Added Table 6 to show the low power mode power dissipation for D3warm mode. • In Table 8 corrected SYS_CLK_IN frequency range from 25–66 MHz to 24–66.67 MHz. • Added Section 8.4, “eTSEC IEEE 1588 AC Specifications” • In Table 42 changed minimum value of USB input hold t_{USIXKH} from 0 to 1ns • Added Table 43 and Table 44 showing USB clock in specifications • In Table 46, added rows for $t_{LALEHOV}$, $t_{LALETOT1}$, $t_{LALETOT2}$, and $t_{LALETOT3}$ parameters. Added Figure 40. • In Table 50, removed row for rise time (t_{I2CR}). Removed minimum value of t_{I2CF}. Added note 5 stating that the device does not follow the I2C-BUS Specifications version 2.1 regarding the t_{I2CF} AC parameter. • In Table 56, added a note stating: “This specification only applies to GPIO pins that are operating from a 3.3-V supply. See Table 63 for the power supply listed for the individual GPIO signal.” [• Added Table 57 to show DC characteristics for GPIO pins supplied by a 2.5-V supply. Same as eTSEC DC characteristics when operating at 2.5 V. • In Section 20, “Clocking,” corrected the sentence “When the device is configured as a PCI agent device, PCI_SYNC_IN is the primary input clock.” to state “When the device is configured as a PCI agent device, PCI_CLK is the primary input clock.” • Added “Value is decided by RCWLR[COREPLL]” to note 1 of Figure 57 • Added paragraph and Figure 59 to Section 22.2, “PLL Power Supply Filtering.” • Added Section 22.4, “SerDes Block Power Supply Decoupling Recommendations • Removed the two figures on PCI undershoot/overshoot voltages and maximum AC waveforms from Section 2.1.2, “Power Supply Voltage Specification,”

Table 73. Document Revision History (continued)

Rev. Number	Date	Substantive Change(s)
1	3/2008	• In Table 63, added LBC_PM_REF_10 & LSRCID3 as muxed with USBDR_PCTL1 • In Table 63, added LSRCID2 as muxed with USBDR_PCTL0 • In Table 63, added LSRCID1 as muxed with USBDR_PWRFAULT • In Table 63, added LSRCID0 as muxed with USBDR_DRIVE_VBUS • In Table 63, moved T1, U2,& V2 from V_{DD} to XCOREVDD. • In Table 63, moved P2, R2, & T3 from V_{SS} to XCOREVSS. • In Table 63, moved P5, & U4 from V_{DD} to XPADVDD. • In Table 63, moved P3, & V4 from V_{SS} to XPADVSS. • In Table 63, removed “Double with pad” for AV_{DD1} and AV_{DD2} and moved AV_{DD1} and AV_{DD2} to Power and Ground Supplies section • In Table 63, added impedance control requirements for SD_IMP_CAL_TX (100 ohms to GND) and SD_IMP_CAL_RX (200 ohms to GND). • In Table 63, updated muxing in pinout to show new options for selecting IEEE 1588 functionality. Added footnote 8 • In Table 63, updated muxing in pinout to show new LBC ECC boot enable control muxed with eTSEC1_MDC • Added pin type information for power supplies. • Removed N1 and N3 from Vss section of Table 63. Added Therm0 and Therm1 (N1 and N3, respectively). Added note 7 to state: “Internal thermally sensitive resistor, resistor value varies linearly with temperature. Useful for determining the junction temperature.” • In Table 65 corrected maximum frequency of Local Bus Frequency from “33–66” to 66 MHz • In Table 65 corrected maximum frequency of PCI from “24–66” to 66 MHz • Added “which is determined by RCWLR[COREPLL],” to the note in Section 20.2, “Core PLL Configuration” about the VCO divider. • Added “(VCOD)” next to VCO divider column in Table 68. Added footnote stating that core_clk frequency must not exceed its maximum, so 2.5:1 and 3:1 *core_clk:csb_clk* ratios are invalid for certain *csb_clk* values. • In Table 69, notes were confusing. Added note 3 for VCO column, note 4 for CSB (*csb_clk*) column, note 5 for USB ref column, and note 6 to replace “Note 1”. Clarified note 4 to explain erratum eTSEC40. • In Table 69, updated note 6 to specify USB reference clock frequencies limited to 24 and 48 for rev. 2 silicon. • Replaced Table 71 “Thermal Resistance for TEPBGAII with Heat Sink in Open Flow”. • Removed last row of Table 19. • Removed 200 MHz rows from Table 21 and Table 5. • Changed VIH minimum spec from 2.0 to 2.1 for clock, PIC, JTAG, SPI, and reset pins in Table 9, Table 47, Table 54, Table 59, and Table 61. • Added Figure 4 showing the DDR input timing diagram. • In Table 19, removed “MDM” from the “MDQS-MDQ/MECC/MDM” text under the Parameter column for the tCISKEW parameter. MDM is an output signal and should be removed from the input AC timing spec table (tCISKEW). • Added “and power” to rows 2 and 3 in Table 10 • Added the sentence “Once both the power supplies...” and PORESET to Section 2.2, “Power Sequencing,” and Figure 3. • In Figure 35, corrected “USB0_CLK/USB1_CLK/DR_CLK” with “USBDR_CLK” • In Table 42, clarified that AC specs are for ULPI only.
0	6/2007	Initial release.